

Notice of References Cited	Application/Control No. 10/527,218	Applicant(s)/Patent Under Reexamination IJIRO ET AL.	
	Examiner Christopher M. Gross	Art Unit 1639	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ijiro et al 2002 International Journal of Nanoscience 1: 597-601
	V	Shimomura et al (2002 Kagaku Kogyo 53:501-505; published July 2002)
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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